

# FWS-2250

INTEL Atom E3826 1.46GHz CPU

## Temperature/Humidity Test Report

Report NO: 14I020009

Summary	<p><input checked="" type="checkbox"/> <b>Pass</b></p> <p><input type="checkbox"/> <b>Fail</b></p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> <b>Pass with Deviation</b></p> <p><b>Comment:</b> _____</p>
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**Issue date**

**2014-05-09**

**Approval**

**Tom Lin**

**Test Engineer**

**Ben Sun**

# Test item list

1.	Test item list -----	2
2.	Configuration of EUT -----	3
3.	Temp./humidity power on/off test -----	4
4.	Temperature rise test-----	5
5.	Temperature variation operation test -----	9
6.	Cold start and hot start test -----	10
7.	High temperature storage test-----	11
8.	Low temperature storage test-----	12
9.	Humidity test-----	13

## Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Temperature rise test	Pass	
3	Temperature variation operation test	Pass	
4	Cold start and hot start test	Pass	
5	High temperature storage test	Pass	
6	Low temperature storage test	Pass	
7	Humidity test	Pass	

# Configuration of EUT

## Test Product: FWS-2250

### Sample Configuration & Quantity Under Test:

1. CPU: Intel Atom E3826 1.46GHz
2. BIOS Ver.: FWS-2250 R0.B (K225AM 0B 01/03/2014)
3. Chipset: N/A
4. Memory: Transcend DDR3L 1333MHz 2G
5. USB Flash: Transcend CompactFlash 32GB
6. Test Software: Windows 8.1 / Run PassMark Burn In Test 7.1 Pro
7. ATX Power Supply: FSP040-DGAA1
8. CPU Cooler:



# Temp./humidity power on/off test

**Test Date:** 04-27 ~ 28-2014

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-30 Testing procedures  
Test Db: Damp Heat Test

**Test Equipment:**

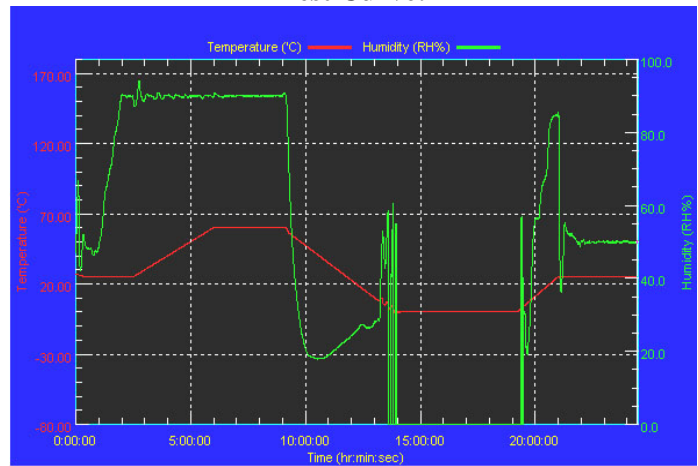
Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
Model: THS-B6T-150+LN2  
Date of Calibration: 06/11/13  
Serial Number: 9095KT

**Temperature & Humidity Power On/Off Test:**

**Testing Specification:**

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

**Test Curve:**



**Test Result:**

Test Method	Actual	Successful	Failure rate
Power On/Off	961/times	961/times	0 %
Note: Failure rate need to be 0%.			

# Temperature rise test

**Test Date:** 05-05-2014

**Test Product:** FWS-2250

**Test Site:** AAeon QE Dept.

**Test Standard:** Refer to EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:

Model: DA100-13-1D

Date of Calibration: 2013/10/01

Serial Number: 12A323190

**Test Condition:**

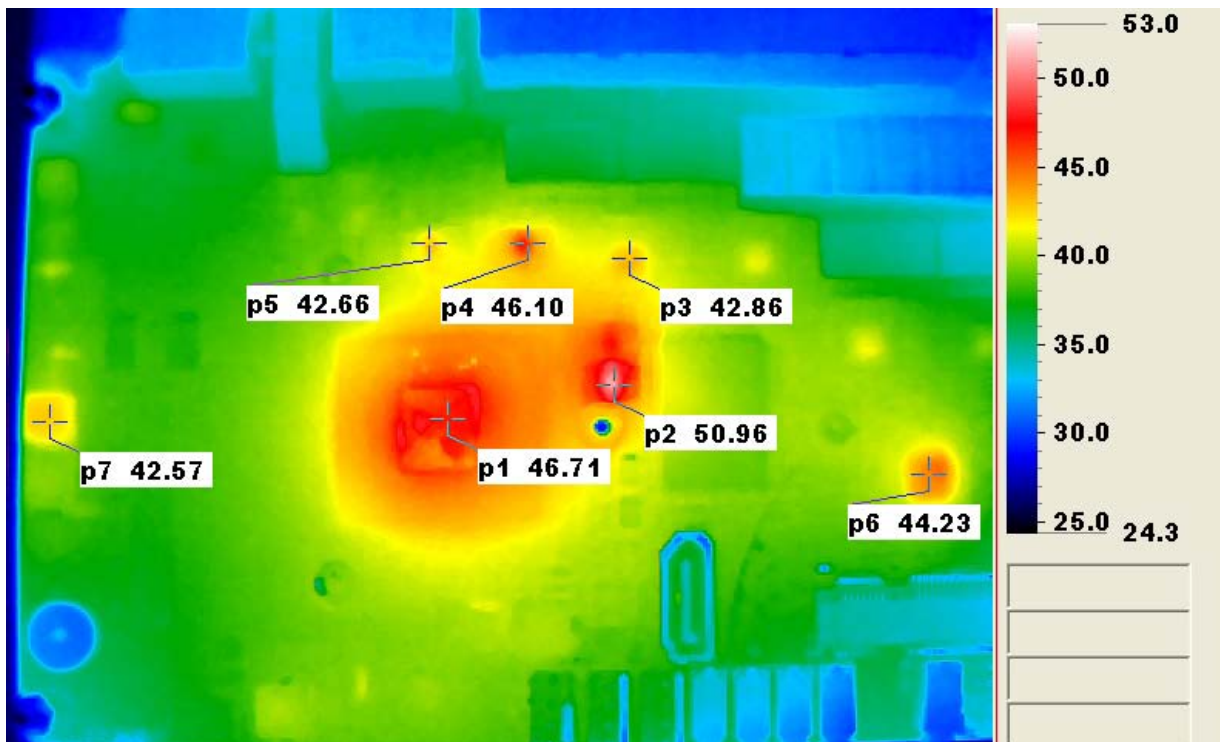
Ambient temperature: 40°C

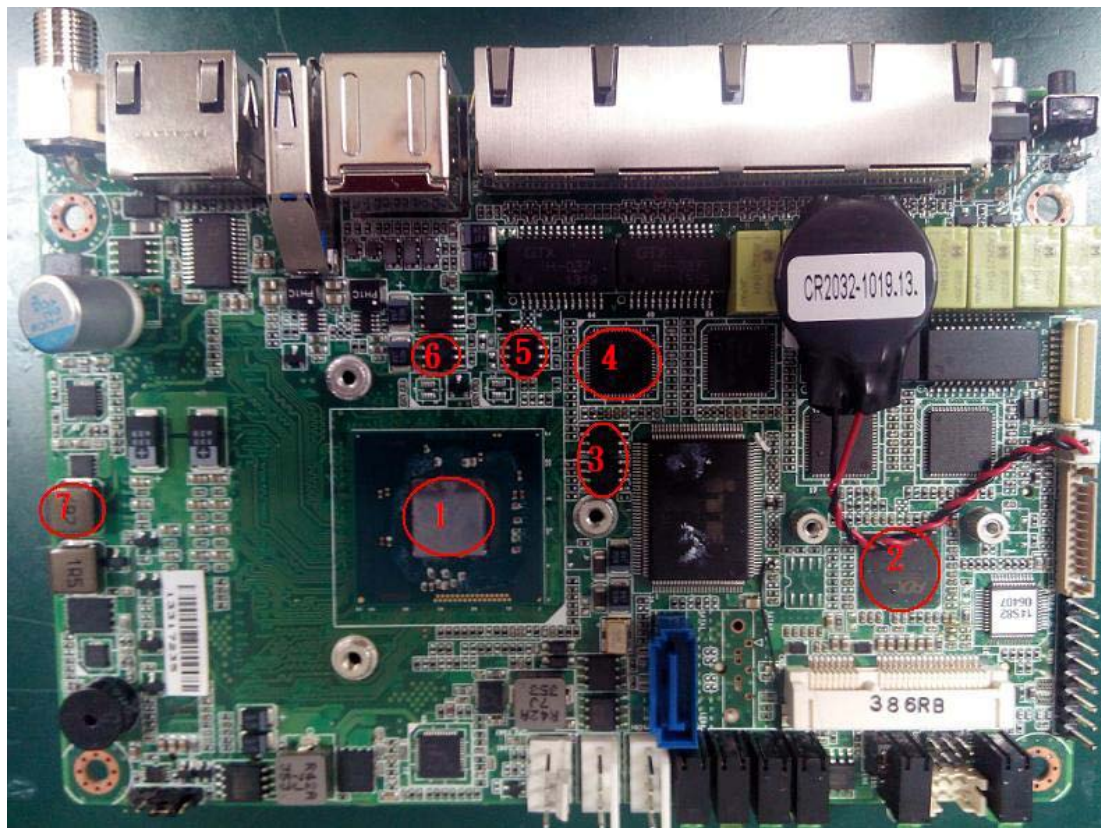
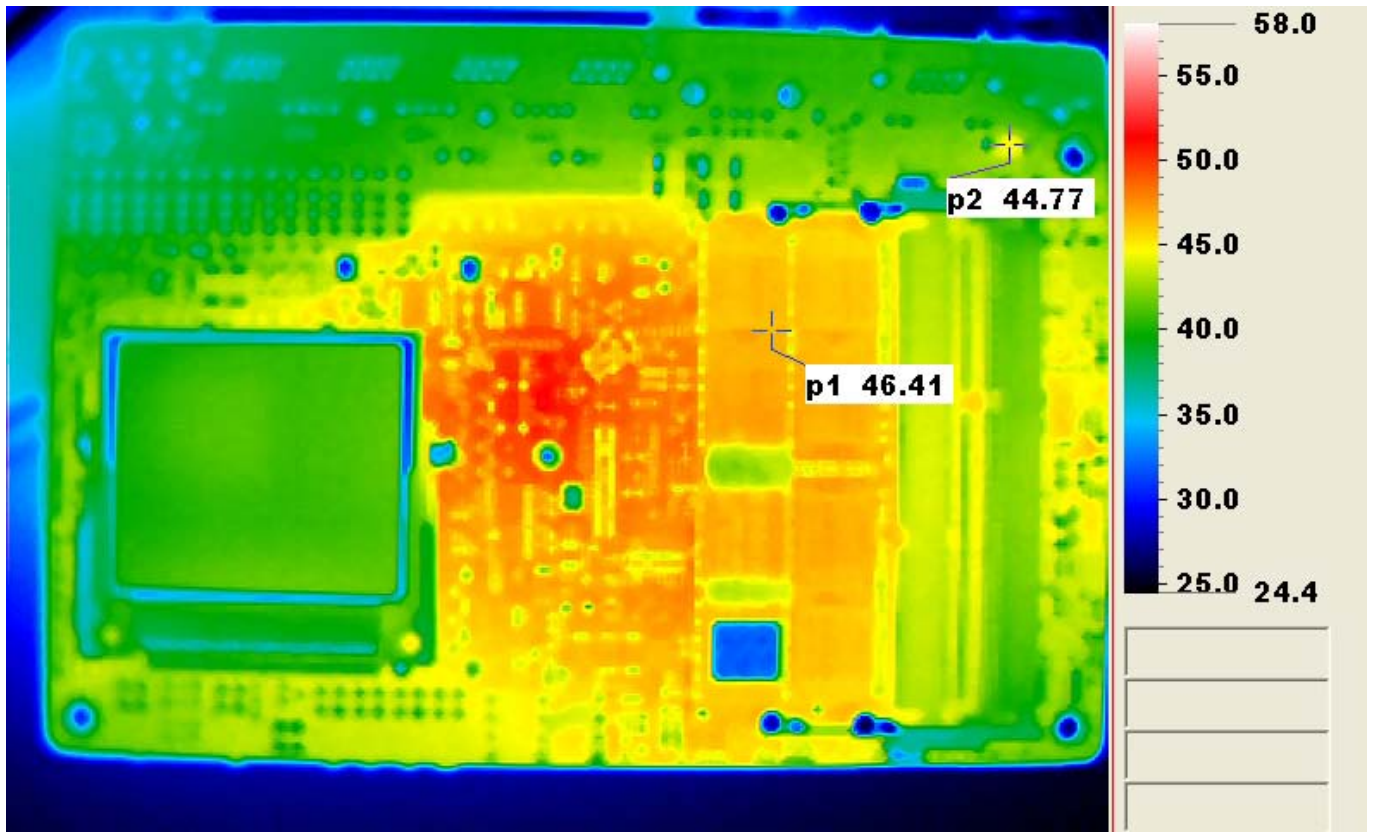
Continuous running till thermal stability (within less than 1°C)

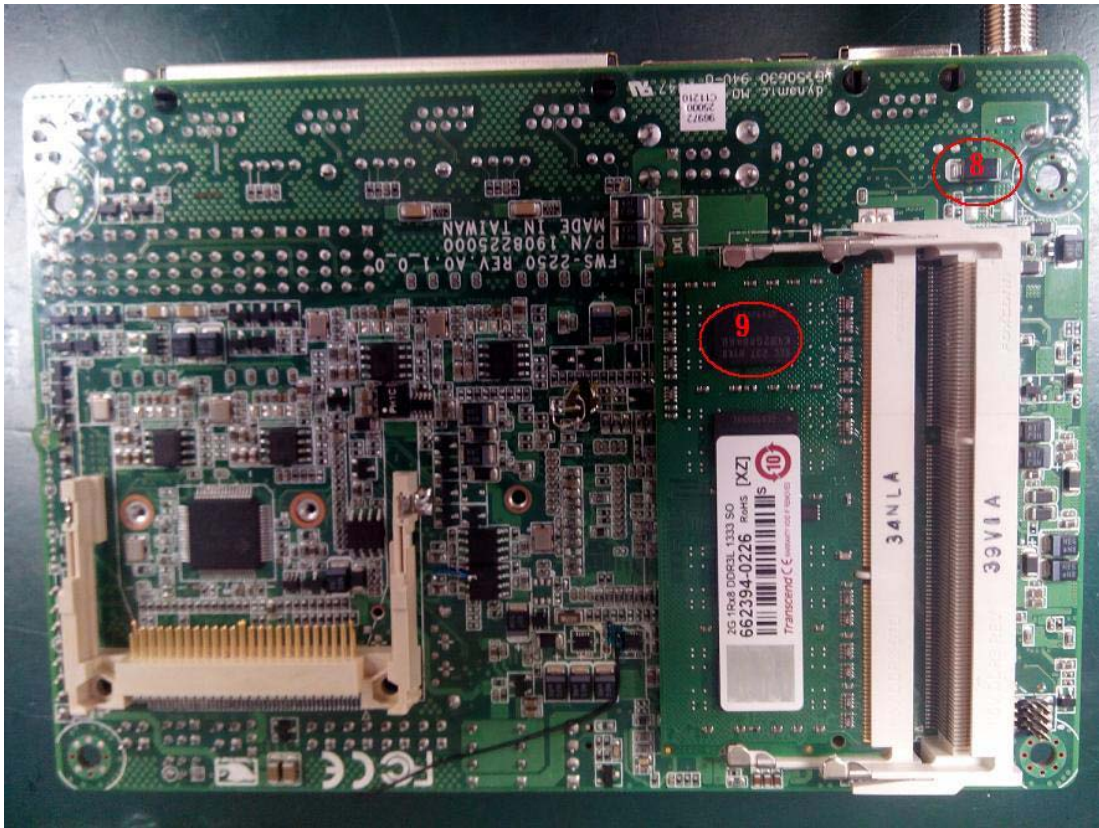
**Test Software:**

Windows 8.1 / Run PassMark Burn In Test 7.1 Pro

**Terminal Recorder:**







# Temperature rise test

## Thermal profile data:

### FWS-2250

Point	Temp. Stage(°C)	Spec	40	Note
01. INTEL CPU.VALLEYVIEW MOBILE.BGA1170P 5W		100	67.1	
02. PCIe-2.0 3port Switch.QFN-136.Thickness=0.9mm SMD.PLX.PEX-8603-AA50NIG		100	82.6	
03. Ultra Low Dropout LDO.SOP-8.SMD.YOBON.YB1283PSP8		100	76.5	
04. PCI-E GigaBit Ethernet Chipset.QFN 64P.SMD.Intel.I211AT		85	77.1	
05. Ultra Low Dropout LDO.SOP-8.SMD.YOBON.YB1283PSP8		100	72.9	
06. Ultra Low Dropout LDO.SOP-8.SMD.YOBON.YB1283PSP8		100	70.1	
07. COIL.4.7uH.20%.SMD.7.1*6.6*3.0mm DCR=37mohm.Idc=5.5Amp Zenithtek.ZPWM-6030M-4R7M		150	69.5	
08. D Schottky.VDC=40V.3A.SMD.DO-214AC Barrier Rectifiers Willas.SK34A		100	66.5	
09. Memory		100	70.8	
10. Chassis Surface Temperature - 1		N/A	56.5	
11. Chamber Air Temperature		N/A	40.3	
<b>Note(*):</b> <b>1. "Tc"</b> indicates the component's case maximum temperature value specified in its datasheet. <b>2. "Tm"</b> indicates the measured Tc value under working environmental temperature within product specification. <b>3. Judgment Criteria:</b> <b>- Fail</b> : $T_m > T_c$ ; The measured value is over specification. <b>- Margin Pass</b> : $T_c > T_m > T_c - 5^\circ\text{C}$ ; The measured value is within specification with margin. It is strongly recommended to add thermal dissipation design for better reliability. <b>- Pass</b> : $T_m < T_c - 5^\circ\text{C}$ ; The measured value is with safety margin. <b>4. Defect NO.</b>				

## Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-2250)

## Test Result:

No issues were found during the temperature rise operation test.



# Temperature variation operation test

**Test Date:** 04-25 ~ 28-2014

**Test Site:** AAEON QE Dept.

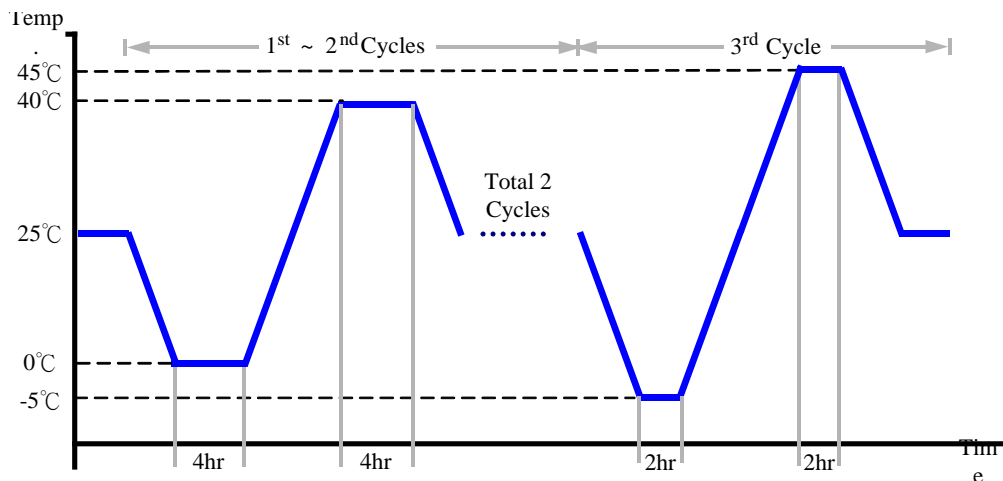
**Test Standard:** Refer to IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
Model: THS-B6T-150+LN2  
Date of Calibration: 06/11/13  
Serial Number: 9095KT

**Temperature & Humidity Cycle Test:**

1. Test Low Temperature: 0°C (1~2 cycles)  
-5°C (3<sup>rd</sup> cycle)
2. Test High Temperature: 40°C (1~2 cycles)  
45°C (3<sup>rd</sup> cycle)
3. Test dwell time: 4Hrs (1~2 cycles)  
2Hrs (3<sup>rd</sup> cycle)
4. Temperature slope: 2°C/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



**Test Result:**

No issues were found during the temperature variation operation test.

# Cold start and hot start test

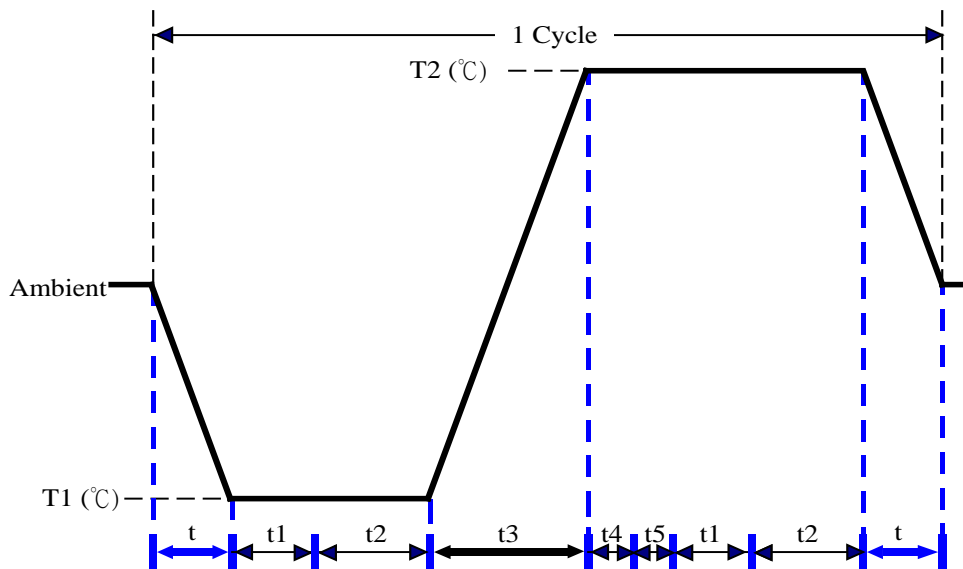
**Test Date:** 04-28 -2013

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
Model: THS-B6T-150+LN2  
Date of Calibration: 06/11/13  
Serial Number: 9095KT

**Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t,t3 = temprature slope  
t, t1: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3,t4: Run PassMark Burn In Test  
t5: Windows 8.1 Software restart test 2 times  
Test Software:Windows 8.1

**Test Result:**

- a. No issues were found during the cold start test.
- b. No issues were found during the hot start test.

# High temperature storage test

**Test Date:** 04-29 ~ 30-2013

**Test Product:** FWS-2250

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

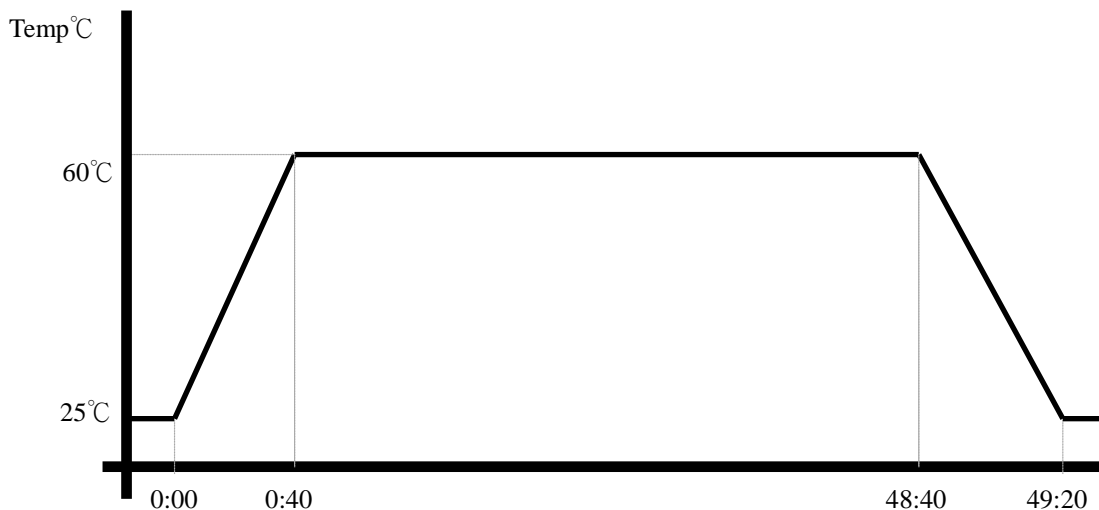
Model: THS-D4H+-100

Date of Calibration: 10/09/13

Serial Number: 2582

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows 8.1 / Run PassMark Burn In Test 7.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (FWS-2250)

**Test Result:**

No issues were found after the high temperature storage test.

# Low temperature storage test

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**Test Date:** 05-5 ~ 06-2014

**Test Product:** FWS-2250

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

Model: THS-D4H+-100

Date of Calibration: 10/09/13

Serial Number: 2582

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows 8.1 / Run PassMark Burn In Test 7.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (FWS-2250)

**Test Result:**

No issues were found after the low temperature storage test.

# Humidity test

**Test Date:** 05-07~8-2014

**Test Product:** FWS-2250

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

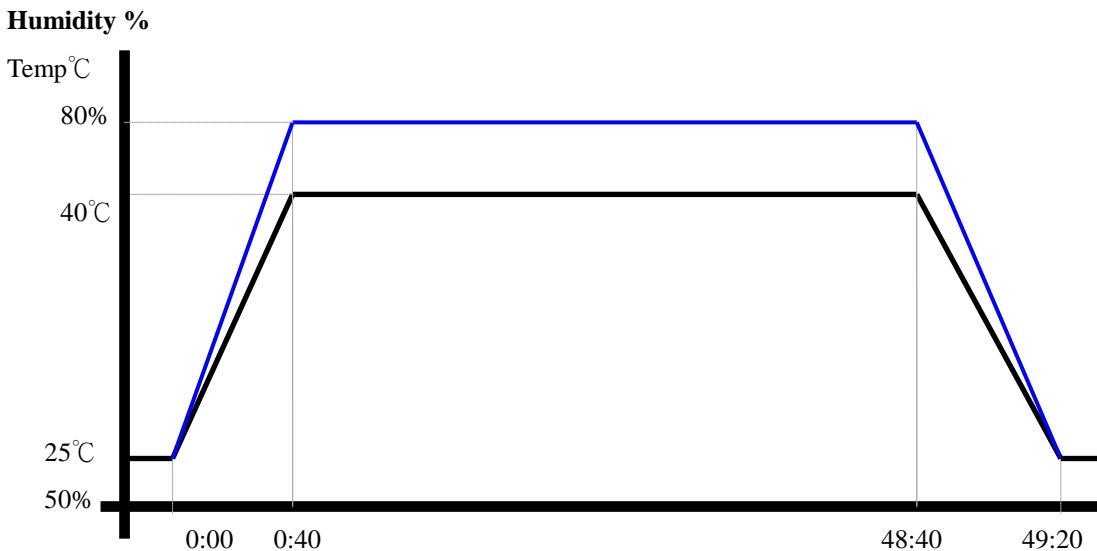
Model: THS-D4H+-100

Date of Calibration: 10/09/13

Serial Number: 2582

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 80%RH
3. Test Times: 48Hrs
4. Test Software: Windows 8.1 / Run PassMark Burn In Test 7.0 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (FWS-2250)

**Test Result:**

No issues were found after the humidity storage test.